

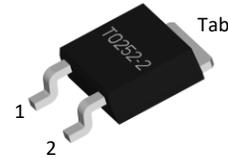
# Silicon Carbide Merged PN-Schottky Diode

## 1200V SiC MPS High Power Rectifier – Cheetah Series



### Product Information:

Cathode  Anode



**TO-252-2L**

### Features

- Low Capacitive Charge ( $Q_C$ )
- Low Profile & Low Parasitic Inductance Packaging
- Zero Reverse Recovery and zero Forward Recovery
- Ultra-Low Switching Loss
- Optimized for High Speed Applications
- Compact MSL-1 SMT Package
- RoHS Compliant and Halogen Free

Terminal	Packaging Type
	TO-252-2L
Anode	2
Cathode	1, Tab

### Benefits

- Higher System Efficiency
- Increase Parallel Device Convenience
- Enable High Temperature Application
- Allow High Frequency Operation
- Realize Compact and Lightweight Systems
- High Reliability

### Potential Applications

- Industrial Switching Mode Power Supply
- Power Factor Correction
- Renewable Energy

### Key Performance Parameters

Parameter	Symbol	Value	Unit
DC Blocking Voltage	$V_R$	1200	V
Nominal Forward Current	$I_{F,NOM}$	2	A
Total Capacitive Charge	$Q_C$	14.2	nC
Capacitance Stored Energy	$E_C$	4.2	$\mu$ J
Junction & Storage Temperature	$T_J, T_{stg}$	-55 to 175	$^{\circ}$ C
Continuous Forward Current	$I_{F,max(cont.)}$	8.8	A
$I^2t$ Value	$\int i^2 dt$	0.8	A <sup>2</sup> s
Power Dissipation	$P_{tot}$	50	W

Part Number	Package	Marking
FC12002A	TO-252-2L	FC12002
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For further information about comparable products, please contact ([www.fastsic.com](http://www.fastsic.com)).

**Maximum Ratings:**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Continuous Forward Current	$I_F$	--	--	2 7 8.8	A	$T_c \leq 163^\circ\text{C}$ , Duty=100% $T_c \leq 75^\circ\text{C}$ , Duty=100% $T_c \leq 25^\circ\text{C}$ , Duty=100%
Non-Repetitive Forward Surge Current, Sinusoidal Halfwave	$I_{F,SM}$	--	--	13		$T_c = 25^\circ\text{C}$ , $t_p = 10\text{ms}$
Non-Repetitive Peak Forward Surge Current	$I_{F,max}$	--	--	342		$T_c = 25^\circ\text{C}$ , $t_p = 10\mu\text{s}$
$I^2t$ Value	$\int i^2 dt$	--	--	0.8	A <sup>2</sup> s	$T_c = 25^\circ\text{C}$ , $t_p = 10\text{ms}$
Repetitive Peak Reverse Voltage	$V_{RRM}$	--	--	1200	V	$T_c = 25^\circ\text{C}$
Power Dissipation	$P_{tot}$	--	--	50	W	$T_c = 25^\circ\text{C}$
		--	--	33		$T_c = 75^\circ\text{C}$
Junction Temperature	$T_j$	-55	--	175	°C	--
Storage Temperature	$T_{stg}$	-55	--	175		
Soldering Temperature	$T_L$	--	--	260		

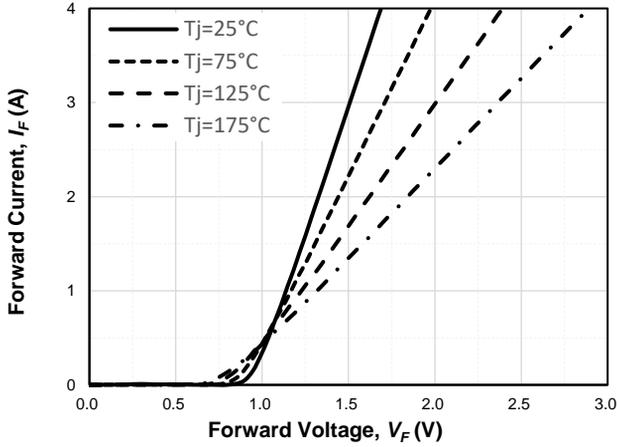
**Electrical Characteristics:**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
<b>DC Characteristics</b>						
DC Blocking Voltage	$V_{DC}$	1200	--	--	V	$T_j = 25^\circ\text{C}$
Forward Voltage	$V_F$	--	1.33 1.85	1.55 --		$I_F = 2\text{A}$ , $T_j = 25^\circ\text{C}$ $I_F = 2\text{A}$ , $T_j = 175^\circ\text{C}$
Reverse Current	$I_R$	--	<0.1 <1	5 --	μA	$V_R = 1200\text{V}$ , $T_j = 25^\circ\text{C}$ $V_R = 1200\text{V}$ , $T_j = 175^\circ\text{C}$
<b>AC Characteristics</b>						
Total Capacitive Charge	$Q_C$	--	14.2	--	nC	$V_R = 800\text{V}$ , $T_j = 25^\circ\text{C}$
Total Capacitance	$C_j$	--	139	--	pF	$V_R = 1\text{V}$ , $f = 1\text{MHz}$ , $T_j = 25^\circ\text{C}$
			14			$V_R = 400\text{V}$ , $f = 1\text{MHz}$ , $T_j = 25^\circ\text{C}$
			11			$V_R = 800\text{V}$ , $f = 1\text{MHz}$ , $T_j = 25^\circ\text{C}$
Capacitance Stored Energy	$E_C$	--	4.2	--	μJ	$V_R = 800\text{V}$ , $T_j = 25^\circ\text{C}$

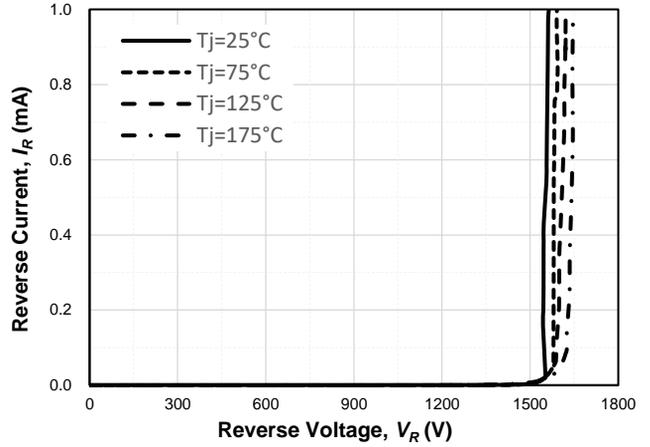
**Thermal Characteristics:**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Thermal Impedance, junction – case	$R_{th-jc}$	--	3	--	K/W	--
Thermal Impedance, junction – ambient	$R_{th-ja}$	--	40	--		Device on PCB, with 6 cm <sup>2</sup> of cooling area

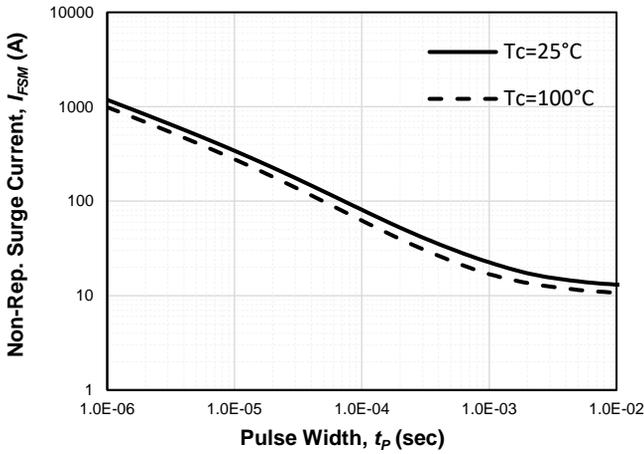
**Electrical Characteristics Diagrams**



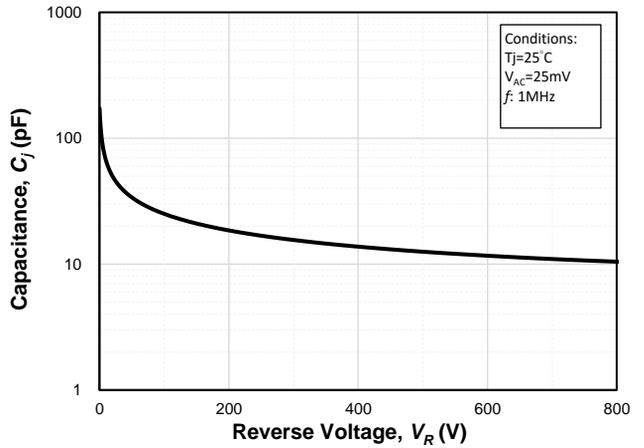
**Fig. 1 Forward Characteristics**



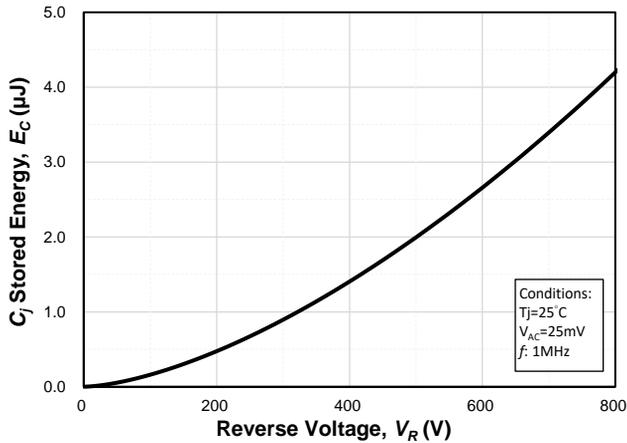
**Fig. 2 Reverse Characteristics**



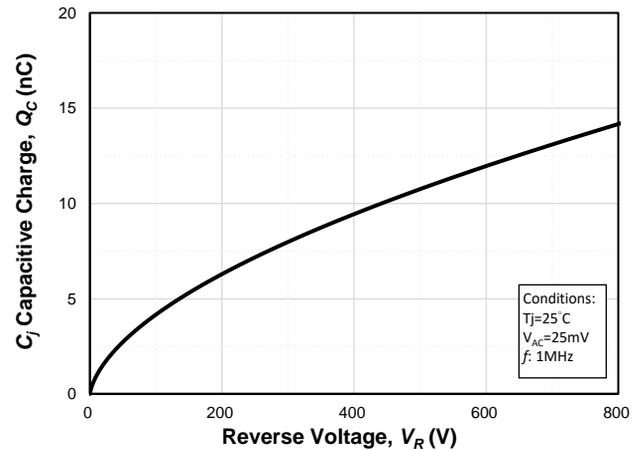
**Fig. 3 Non-repetitive Peak Forward Surge Current vs. Pulse Width**



**Fig. 4 Capacitance vs. Reverse Voltage**

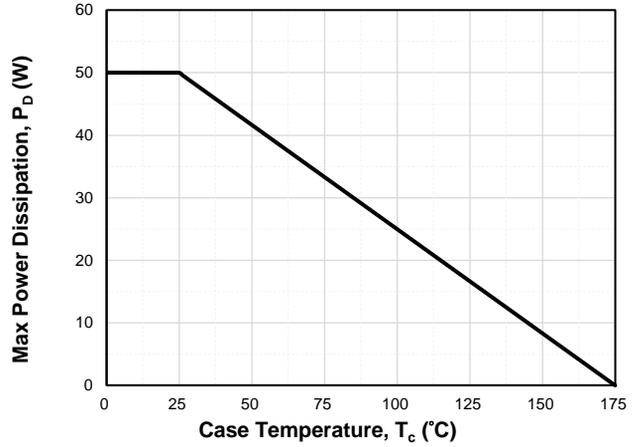
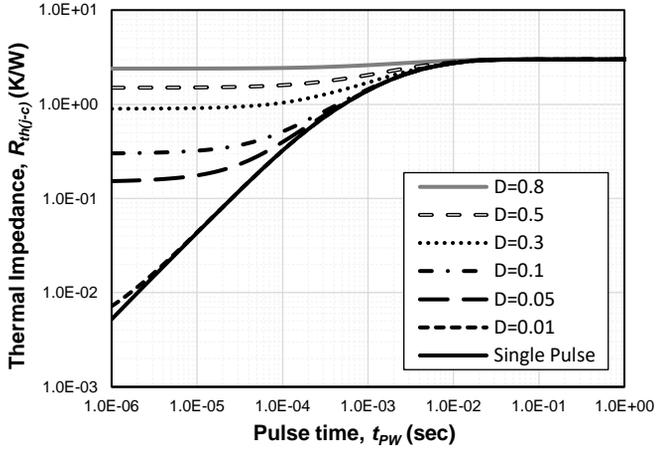


**Fig. 5 Capacitance Stored Energy vs. Reverse Voltage**



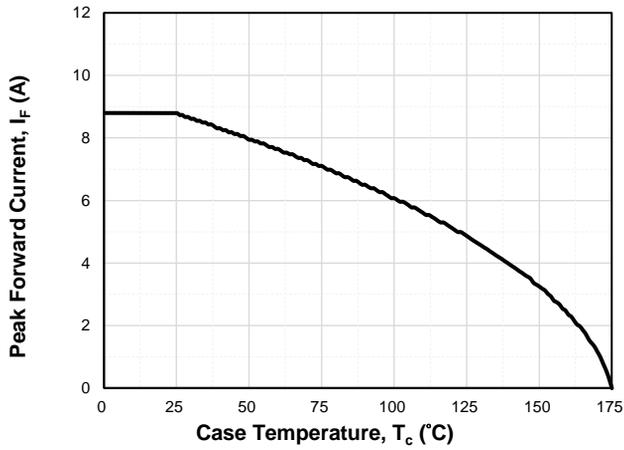
**Fig. 6 Capacitive Charge vs. Reverse Voltage**

**Electrical Characteristics Diagrams**



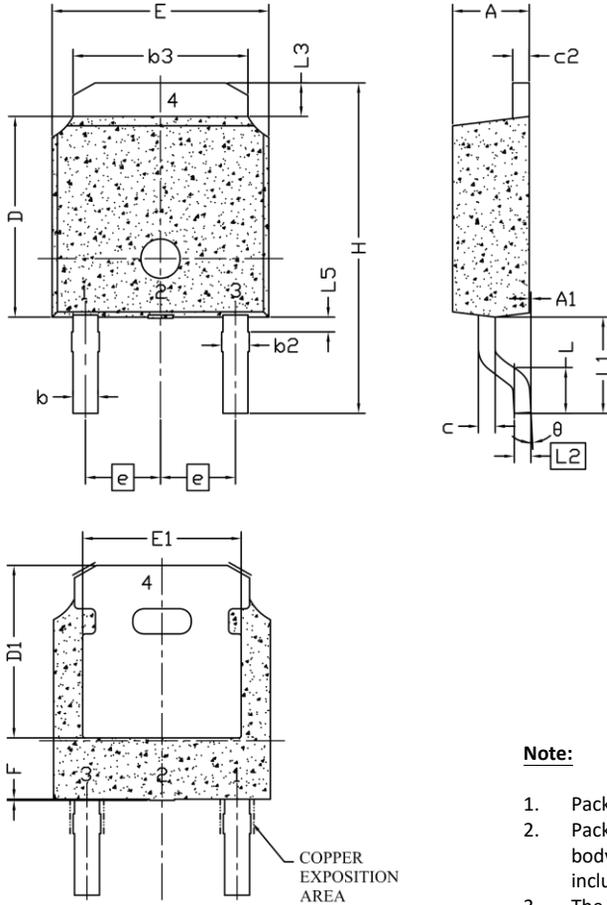
**Fig. 7 Typ. Transient Thermal Impedance  $R_{th-jc}$**

**Fig. 8 Power Dissipation**



**Fig. 9 Continuous  $I_F$  De-rating**

**Package Outline (TO-252-2L)**

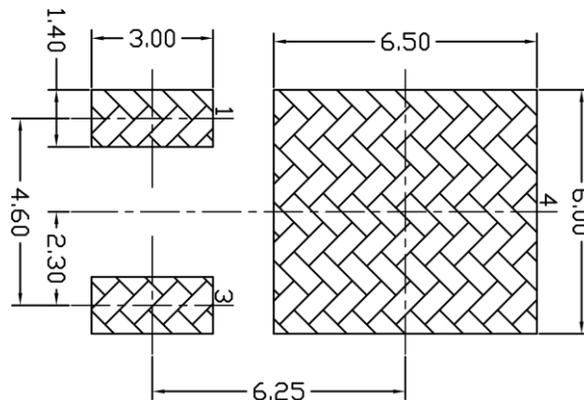


Symbol	Dimension (Millimeters)		
	Min.	Nom.	Max.
E	6.40	6.60	6.73
L	1.40	1.52	1.77
L1	2.743 REF.		
L2	0.508 BSC.		
L3	0.89	--	1.27
L5	--	--	--
D	6.00	6.10	6.22
H	9.40	10.00	10.40
b	0.64	0.76	0.88
b2	0.77	0.84	1.14
b3	5.21	5.34	5.46
e	2.286 BSC.		
A	2.20	2.30	2.38
A1	0.00	--	0.127
c	0.46	0.50	0.60
c2	0.46	0.50	0.58
D1	5.21	--	--
E1	4.40	--	--
F	--	--	0.45
θ	0°	--	10°

**Note:**

1. Package body sizes exclude mold flash, protrusion, or gate burrs.
2. Package body sizes determined at the outermost extremes of the plastic body exclusive of mold flash, gate burrs, and inter-lead flash, but including any mismatch between the top and bottom of the plastic body.
3. The package top may be smaller than the package bottom.
4. Dimension "b" does not include dambar protrusion. Allowable dambar protrusion shall be 0.1 mm total in excess of "b" dimension at the maximum material condition. The dambar cannot be located on the lower radius of the foot.
5. Dimension "F" is mold flash.

**Land Pattern (Only for Reference)**



## Revision History

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Date	Revision	Changes
24.06	Preliminary	1 <sup>st</sup> issue

## Important Note (Disclaimer)

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